

FAST Products

FEATURES

- Combines demultiplexer and 8-bit latch
- Serial-to-parallel capability
- Output from each storage bit available
- Random (addressable) data entry
- Easily expandable
- Common reset input
- Useful as a 1-of-8 active-High decoder

DESCRIPTION

The 74F259 addressable latch has four distinct modes of operation which are selectable by controlling the Master Reset (\overline{MR}) and Enable (\overline{E}) inputs (see Function Table). In the addressable latch mode, data at the Data inputs is written into the addressed latches. The addressed latches will follow the Data input with all unaddressed latches remaining in their previous states. In the store mode, all latches remain in their previous states and are unaffected by the Data or Address inputs. To eliminate the possibility of entering erroneous data in the latches, the Enable should be held High (inactive) while the address lines are changing. In the 1-of-8 decoding or demultiplexing mode ($\overline{MR}=\overline{E}=\text{Low}$), addressed outputs will follow the level of the Data input, with all other outputs Low. In the Master Reset mode, all outputs are Low and unaffected by the Address and Data inputs.

Product Specification

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F259	7.5ns	31mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$; $T_A = 0^\circ\text{C to } +70^\circ\text{C}$
16-Pin Plastic DIP	N74F259N
16-Pin Plastic SO	N74F259D

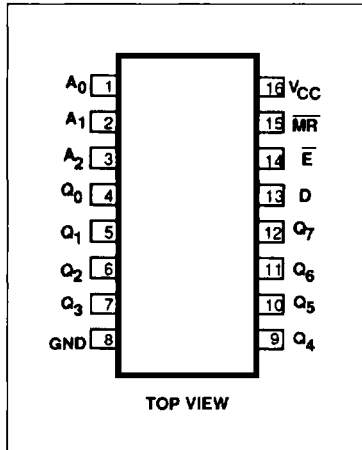
INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D	Data input	1.0/1.0	20 μ A/0.6mA
A_0, A_1, A_2	Address inputs	1.0/1.0	20 μ A/0.6mA
\overline{E}	Enable input (active Low)	1.0/1.0	20 μ A/0.6mA
\overline{MR}	Master Reset inputs (active Low)	1.0/1.0	20 μ A/0.6mA
$Q_0 - Q_7$	Data outputs	50/33	1.0mA/20mA

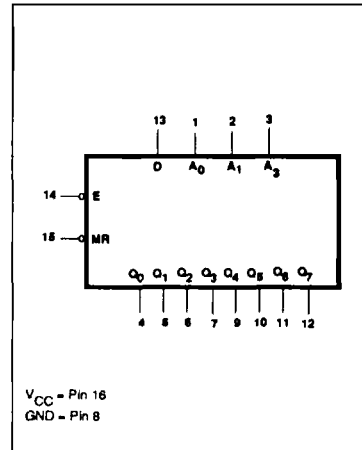
NOTE:

One (1.0) FAST Unit Load is defined as: 20 μ A in the High state and 0.6mA in the Low state.

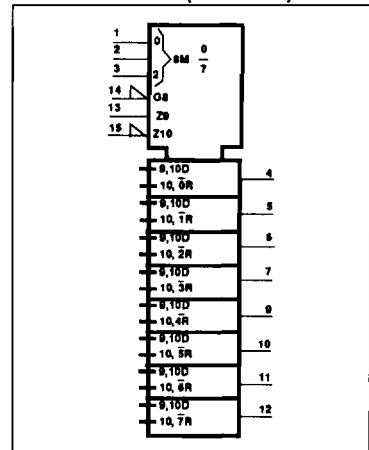
PIN CONFIGURATION



LOGIC SYMBOL



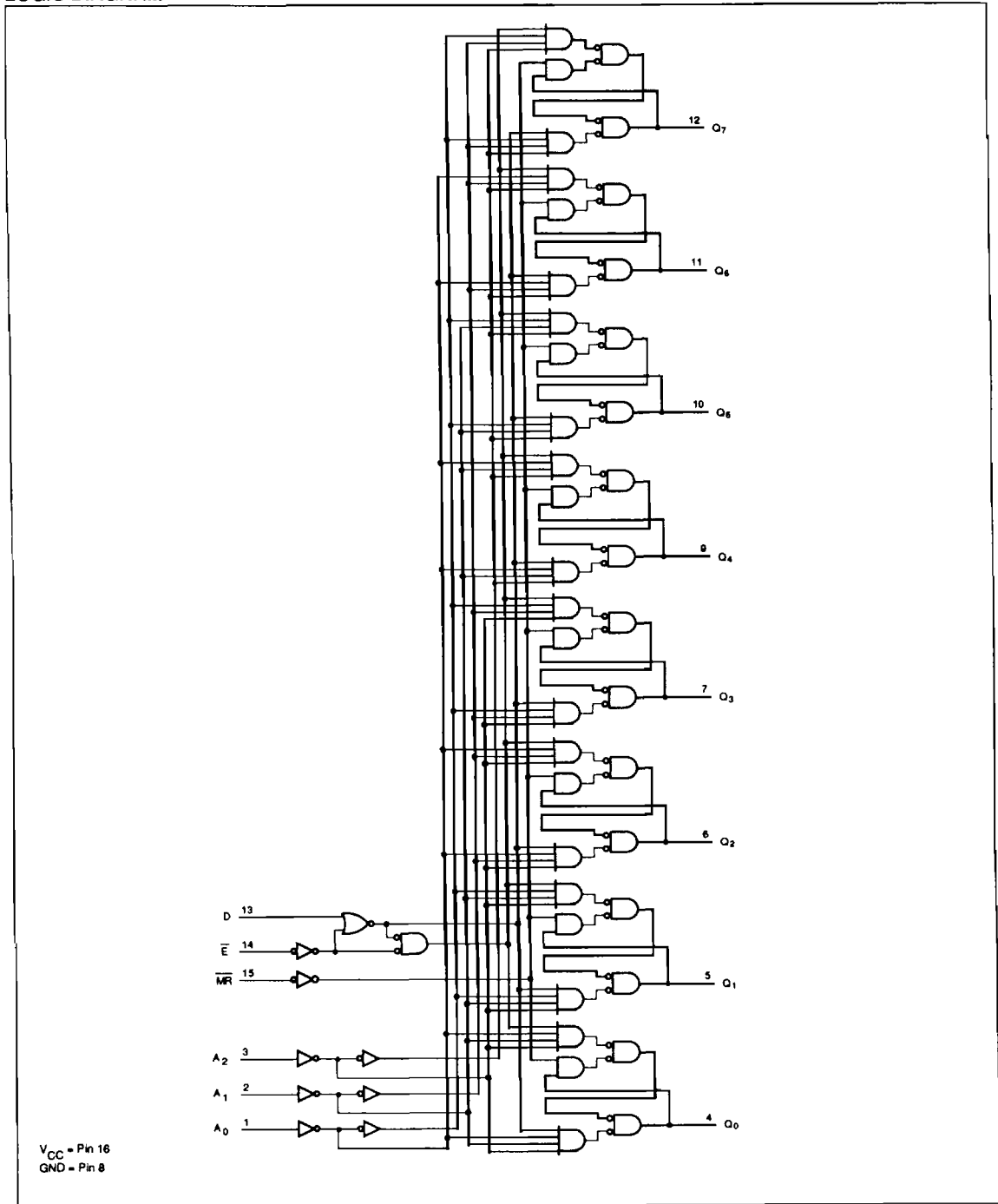
LOGIC SYMBOL (IEEE/IEC)



Latch

FAST 74F259

LOGIC DIAGRAM



Latch

FAST 74F259

FUNCTION TABLE

INPUTS						OUTPUTS								OPERATING MODE
\overline{MR}	\overline{E}	D	A ₀	A ₁	A ₂	Q ₀	Q ₁	Q ₂	Q ₃	Q ₄	Q ₅	Q ₆	Q ₇	
L	H	X	X	X	L	L	L	L	L	L	L	L	L	Master Reset
L	L	d	L	L	L	Q=d	L	L	L	L	L	L	L	Demultiplex (active-High decoder when D=H)
L	L	d	H	L	L	L	Q=d	L	L	L	L	L	L	
L	L	d	L	H	L	L	L	Q=d	L	L	L	L	L	
.	
L	L	d	H	H	H	L	L	L	L	L	L	L	Q=d	
H	H	X	X	X	X	q ₀	q ₁	q ₂	q ₃	q ₄	q ₅	q ₆	q ₇	Store (do nothing)
H	L	d	L	L	L	Q=d	q ₁	q ₂	q ₃	q ₄	q ₅	q ₆	q ₇	Addressable Latch
H	L	d	H	L	L	q ₀	Q=d	q ₂	q ₃	q ₄	q ₅	q ₆	q ₇	
H	L	d	L	H	L	q ₀	q ₁	Q=d	q ₃	q ₄	q ₅	q ₆	q ₇	
.	
H	L	d	H	H	H	q ₀	q ₁	q ₂	q ₃	q ₄	q ₅	q ₆	Q=d	

H = High voltage level

L = Low voltage level

X = Don't care

d = High or Low data one setup time prior to the Low-to-High Enable transition

q = Lower case letters indicate the state of the referenced output established during the last cycle in which it was addressed or cleared.

ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to +V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _A	Operating free-air temperature range	0 to +70	°C
T _{STG}	Storage temperature	-65 to +150	°C

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RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current			-1	mA
I_{OL}	Low-level output current			20	mA
T_A	Operating free-air temperature range	0		70	°C

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT	
			Min	Typ ²	Max		
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$ $V_{IH} = \text{MIN}, I_{OH} = \text{MAX}$	$\pm 10\%V_{CC}$	2.5		V	
			$\pm 5\%V_{CC}$	2.7	3.4	V	
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$ $V_{IH} = \text{MIN}, I_{OL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.35	0.50	V
			$\pm 5\%V_{CC}$		0.35	0.50	V
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$		-0.73	-1.2	V	
I_I	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 7.0V$			100	μA	
I_{IH}	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7V$			20	μA	
I_{IL}	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5V$			-0.6	mA	
I_{OS}	Short circuit output current ³	$V_{CC} = \text{MAX}$		-60	-150	mA	
I_{CC}	Supply current (total)	$V_{CC} = \text{MAX}$		24	46	mA	
				37	75	mA	

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5V, T_A = 25^\circ C$.
- To reduce the effect of external noise during test.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

Latch

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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V } \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation delay D to Q_n	Waveform 1	4.0 3.0	7.0 5.0	9.0 7.0	4.0 2.5	10.0 7.5	ns
t_{PLH} t_{PHL}	Propagation delay \bar{E} to Q_n	Waveform 1	4.5 3.0	8.0 5.0	10.5 7.0	4.5 3.0	12.0 8.0	ns
t_{PLH} t_{PHL}	Propagation delay A_n to Q_n	Waveform 2	5.0 4.0	10.0 8.5	14.0 9.5	5.0 4.0	14.5 10.0	ns
t_{PHL}	Propagation delay \overline{MR} to Q_n	Waveform 3	5.0	7.0	9.0	4.5	10.0	ns

AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V } \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
$t_s(H)$ $t_s(L)$	Setup time, High or Low D to \bar{E}	Waveform 4	3.0 6.5			3.0 7.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low D to \bar{E}	Waveform 4	0 0			0 0		ns
$t_s(H)$ $t_s(L)$	Setup time, High or Low A_n to \bar{E}^1	Waveform 5	2.0 2.0			2.0 2.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low A_n to \bar{E}^2	Waveform 5	0 0			0 0		ns
$t_w(L)$	\bar{E} Pulse width, Low	Waveform 1	7.5			8.0		ns
$t_w(L)$	\overline{MR} Pulse width, Low	Waveform 3	3.0			3.0		ns

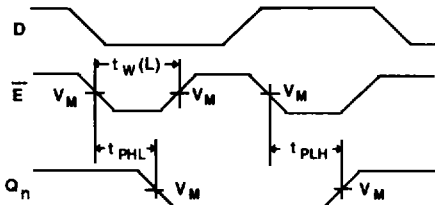
NOTES:

1. The Address to Enable setup time is the time before the High-to-Low Enable transition that the Address must be stable so that the correct latch is addressed and the other latches are not affected.
2. The Address to Enable hold time is the time before the Low-to-High Enable transition that the Address must be stable so that the correct latch is addressed and the other latches are not affected.

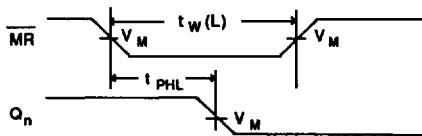
Latch

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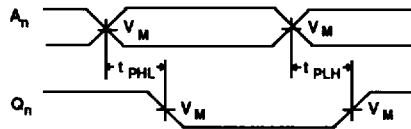
AC WAVEFORMS



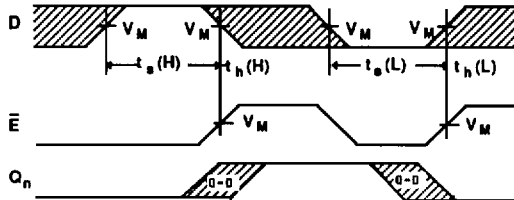
Waveform 1. Propagation Delay, Enable Input To Output, Enable Pulse Width



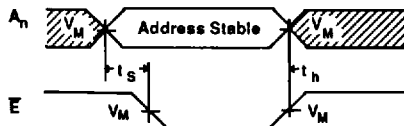
Waveform 3. Master Reset Pulse Width And Master Reset to Output Delay



Waveform 2. Propagation Delay Address To Output



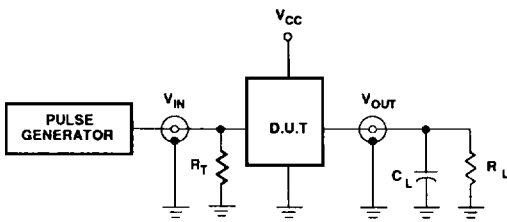
Waveform 4. Data Setup And Hold Times



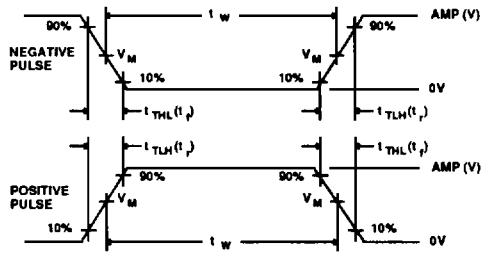
Waveform 5. Address Setup And Hold Times

NOTE: For all waveforms, $V_M = 1.5V$.
The shaded areas indicate when the input is permitted to change for predictable output performance.

TEST CIRCUIT AND WAVEFORMS



Test Circuit For Totem-Pole Outputs



$V_M = 1.5V$

Input Pulse Definition

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_{TLH}	t_{THL}
74F	3.0V	1MHz	500ns	2.5ns	2.5ns